

Correct reuse of complex design units during high level synthesis : verification issues

Dušina, Julia IEEE International High Level Design Validation and Test Workshop, Oakland, California, USA, November 15-16, 1996 : proceedings 1996

Formalization and validation of the std logic-1164 and numeric-std VHDL packages using the nqthm theorem prover

Dušina, Julia; Borriane, Dominique 2nd Workshop on Libraries, Component Modeling and Quality Assurance : proceedings : Toledo, Spain, April, 1997 1997 / p. 169-180

Formalization of finite state machines with data path for the verification of high-level synthesis

Borriane, Dominique; **Dušina, Julia**; Pierre, Laurence XI Brazilian Symposium on Integrated Circuit Design, September 30 - October 3, 1998, Rio de Janeiro, Brazil : proceedings 1998 / p. 99-102: ill

FTGEN - система генерирования функциональных тестов

Ubar, Raimund-Johannes; **Dušina, Julia**; **Zaugarov, Viktor**; Крупнова Е.; **Storožev, Sergei** Proceedings of CAD-93 : new information technologies for science, education and business, Yalta, May 4-13, 1993 1993 / p. 123-125

Functional test program generation for digital systems

Ubar, Raimund-Johannes; Dušina, Julia; **Krupnova, Helena**; **Storožev, Sergei**; **Zaugarov, Viktor** Testmethoden und Zuverlässigkeit von Schaltungen und Systemen : proceedings of the 6th workshop, Vaals (Niederlande), March 6-8, 1994 1994 / p. 14-18: ill

Test generation for control faults in digital systems

Dušina, Julia; **Brik, Marina** BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 325-330: ill

Test program generation for microprocessor systems

Dušina, Julia 1993 https://www.ester.ee/record=b2090526*est

Verification formelle des resultats de la synthese de Haut Niveau : [doktoriväitekiri]

Dušina, Julia 1999

Система генерирования тестов для микропроцессоров

Ubar, Raimund-Johannes; **Dušina, Julia**; **Zaugarov, Viktor**; Крупнова Е.; **Storožev, Sergei** Proceedings of international conference "Technical Diagnostics-93", St.-Peterburg, June 8-10, 1993 1993 / p. 87-89